

### SWITCHING

### N-CHANNEL POWER MOS FET

### INDUSTRIAL USE

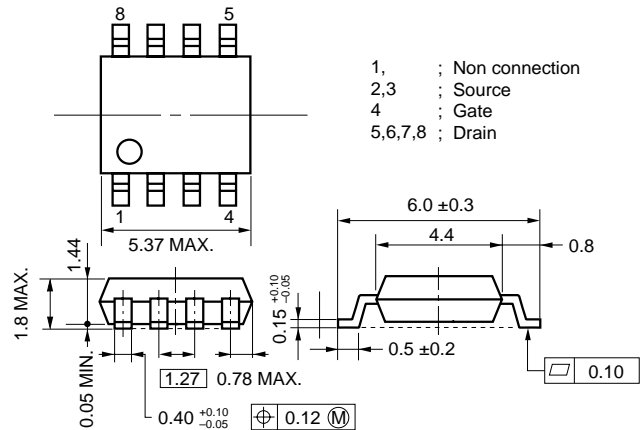
#### DESCRIPTION

This  $\mu$ PA1725 is N-Channel MOS Field Effect Transistor designed for power management applications of notebook computers and so on.

#### FEATURES

- 2.5-V gate drive and low on-resistance
- ★  $R_{DS(on)1} = 21.0 \text{ m}\Omega \text{ MAX.}$  ( $V_{GS} = 4.5 \text{ V}$ ,  $I_D = 3.5 \text{ A}$ )
- ★  $R_{DS(on)2} = 22.0 \text{ m}\Omega \text{ MAX.}$  ( $V_{GS} = 4.0 \text{ V}$ ,  $I_D = 3.5 \text{ A}$ )
- ★  $R_{DS(on)3} = 30.0 \text{ m}\Omega \text{ MAX.}$  ( $V_{GS} = 2.5 \text{ V}$ ,  $I_D = 3.5 \text{ A}$ )
- Low  $C_{iss}$  :  $C_{iss} = 950 \text{ pF TYP.}$
- Built-in G-S protection diode
- Small and surface mount package (Power SOP8)

#### PACKAGE DRAWING (Unit : mm)



#### ORDERING INFORMATION

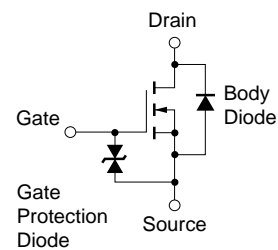
PART NUMBER	PACKAGE
$\mu$ PA1725G	Power SOP8

#### ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ\text{C}$ , All terminals are connected.)

Drain to Source Voltage ( $V_{GS} = 0 \text{ V}$ )	$V_{DSS}$	20	V
Gate to Source Voltage ( $V_{DS} = 0 \text{ V}$ )	$V_{GSS}$	$\pm 12$	V
Drain Current (DC)	$I_{D(DC)}$	$\pm 7$	A
Drain Current (pulse) <sup>Note1</sup>	$I_{D(pulse)}$	$\pm 28$	A
Total Power Dissipation ( $T_A = 25^\circ\text{C}$ ) <sup>Note2</sup>	$P_T$	2.0	W
Channel Temperature	$T_{ch}$	150	$^\circ\text{C}$
Storage Temperature	$T_{stg}$	-55 to +150	$^\circ\text{C}$

- Notes 1.**  $PW \leq 10 \mu\text{s}$ , Duty Cycle  $\leq 1 \%$   
**2.** Mounted on ceramic substrate of  $1200 \text{ mm}^2 \times 2.2 \text{ mm}$

#### EQUIVALENT CIRCUIT



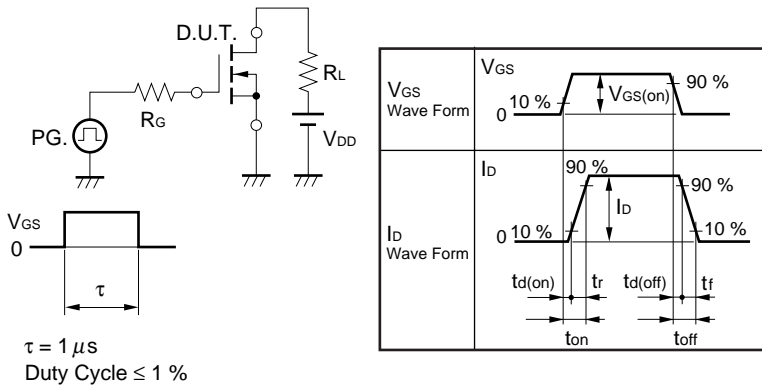
**Remark** The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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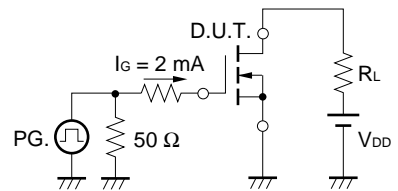
**ELECTRICAL CHARACTERISTICS (T<sub>A</sub> = 25 °C, All terminals are connected.)**

CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
★ Drain to Source On-state Resistance	R <sub>DS(on)1</sub>	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 3.5 A		16.5	21.0	mΩ
	R <sub>DS(on)2</sub>	V <sub>GS</sub> = 4.0 V, I <sub>D</sub> = 3.5 A		17.0	22.0	mΩ
	R <sub>DS(on)3</sub>	V <sub>GS</sub> = 2.5 V, I <sub>D</sub> = 3.5 A		22.0	30.0	mΩ
★ Gate to Source Cut-off Voltage	V <sub>GS(off)</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	0.5	1.0	1.5	V
★ Forward Transfer Admittance	y <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 3.5 A	5.0	11.0		S
Drain Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 0 V			10	μA
Gate to Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> = ±12 V, V <sub>DS</sub> = 0 V			±10	μA
Input Capacitance	C <sub>iSS</sub>	V <sub>DS</sub> = 10 V		950		pF
Output Capacitance	C <sub>oSS</sub>	V <sub>GS</sub> = 0 V		310		pF
Reverse Transfer Capacitance	C <sub>rSS</sub>	f = 1 MHz		160		pF
Turn-on Delay Time	t <sub>d(on)</sub>	I <sub>D</sub> = 3.5 A		30		ns
Rise Time	t <sub>r</sub>	V <sub>GS(on)</sub> = 4.5 V		120		ns
Turn-off Delay Time	t <sub>d(off)</sub>	V <sub>DD</sub> = 10 V		70		ns
Fall Time	t <sub>f</sub>	R <sub>G</sub> = 10 Ω		70		ns
Total Gate Charge	Q <sub>G</sub>	I <sub>D</sub> = 7 A		9.6		nC
Gate to Source Charge	Q <sub>GS</sub>	V <sub>DD</sub> = 16 V		1.7		nC
Gate to Drain Charge	Q <sub>GD</sub>	V <sub>GS</sub> = 4.5 V		4.1		nC
★ Body Diode Forward Voltage	V <sub>F(S-D)</sub>	I <sub>F</sub> = 7 A, V <sub>GS</sub> = 0 V		0.8		V
Reverse Recovery Time	t <sub>rr</sub>	I <sub>F</sub> = 7 A, V <sub>GS</sub> = 0 V		40		ns
Reverse Recovery Charge	Q <sub>rr</sub>	di/dt = 100 A/μs		27		nC

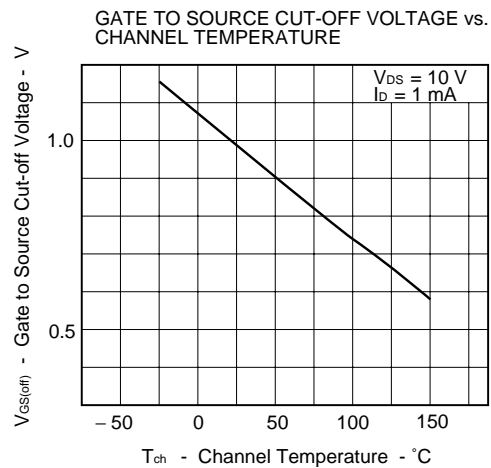
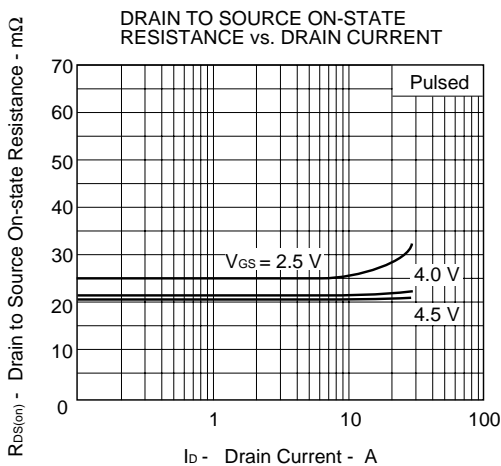
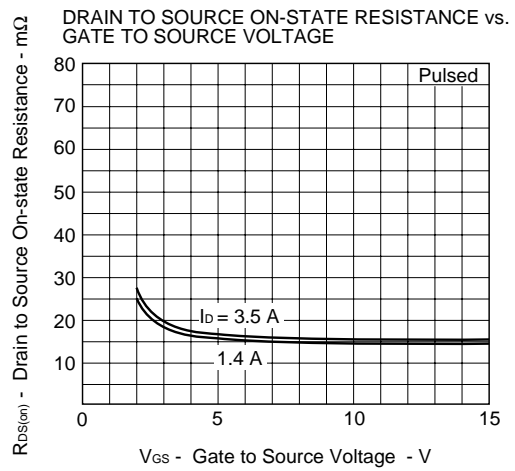
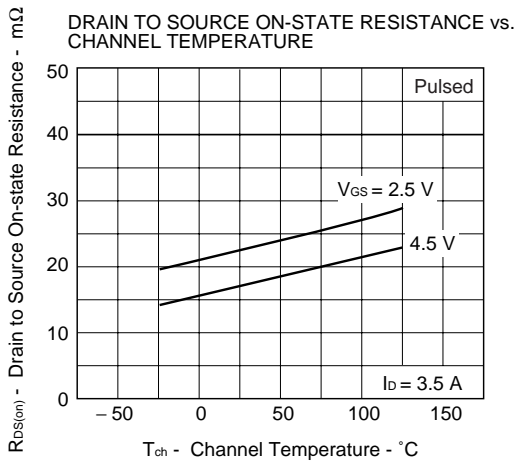
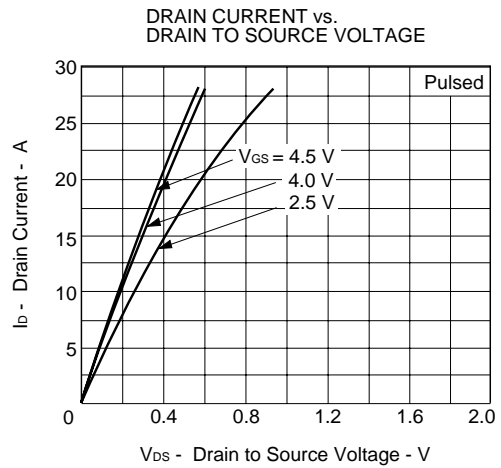
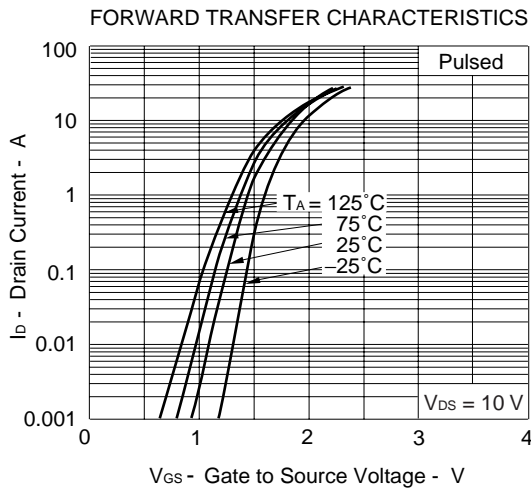
**TEST CIRCUIT 2 SWITCHING TIME**

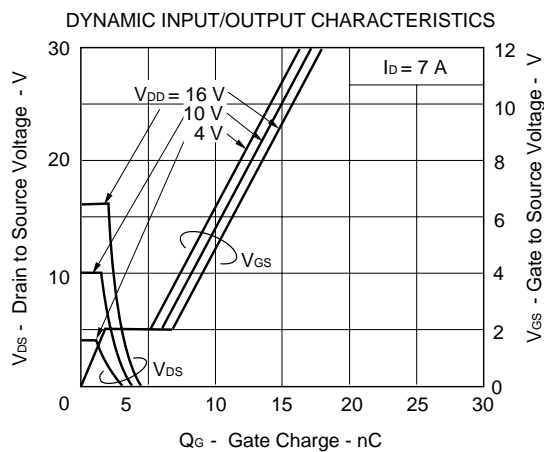
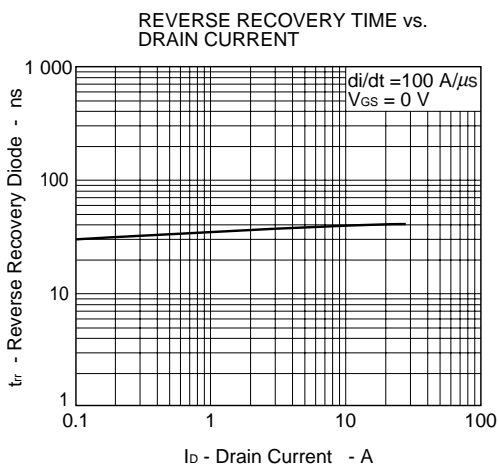
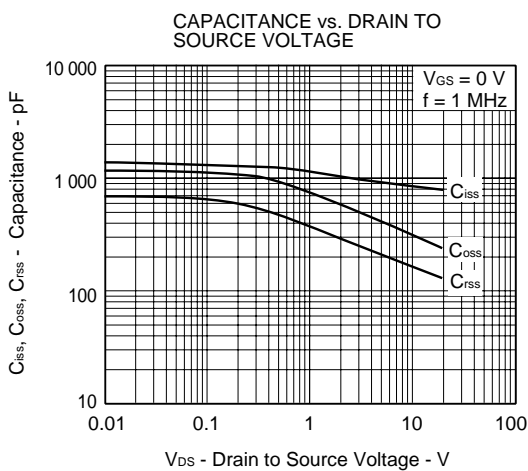
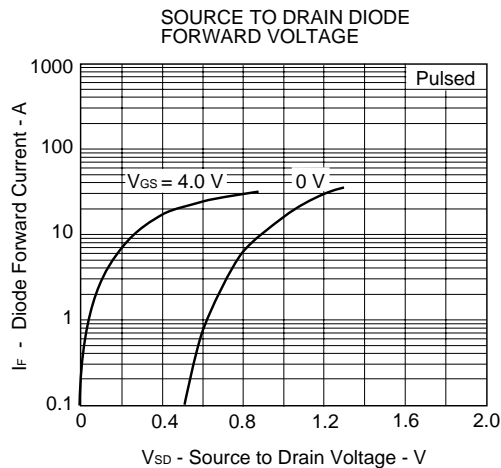
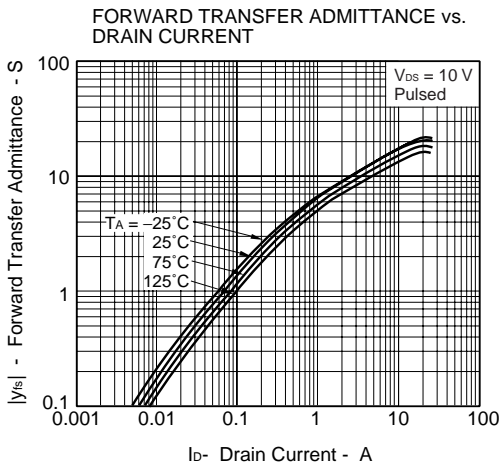


**TEST CIRCUIT 3 GATE CHARGE**

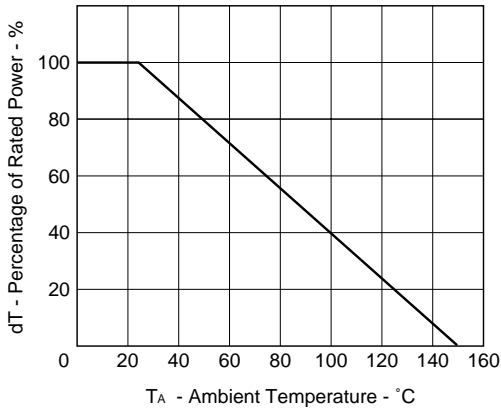


★ TYPICAL CHARACTERISTICS (T<sub>A</sub> = 25 °C , All terminals are connected.)

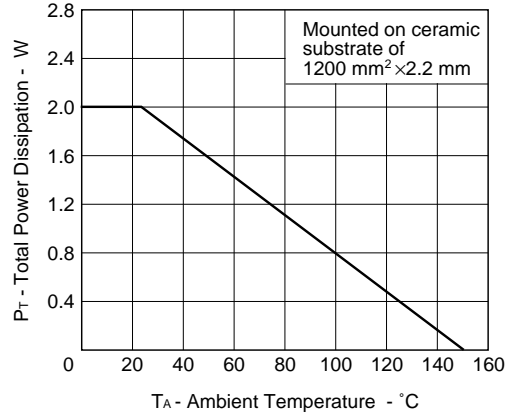




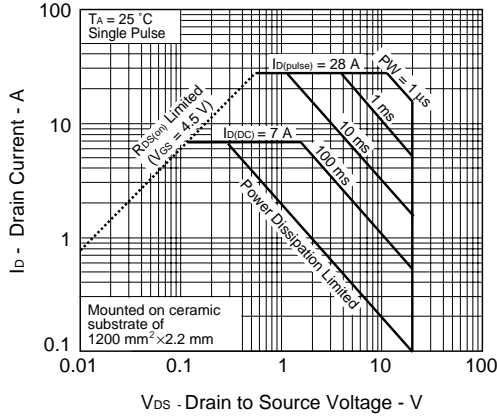
DERATING FACTOR OF FORWARD BIAS SAFE OPERATING AREA



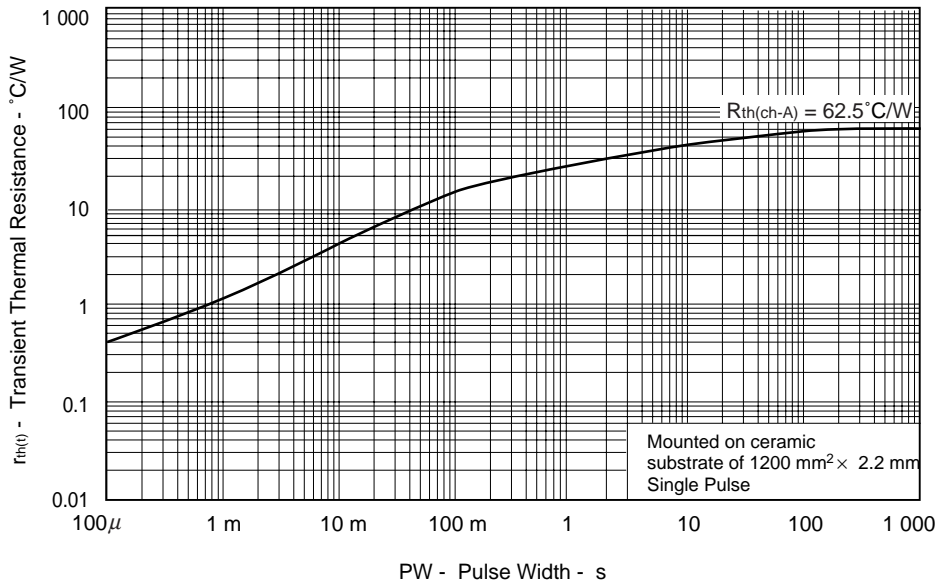
TOTAL POWER DISSIPATION vs. AMBIENT TEMPERATURE



FORWARD BIAS SAFE OPERATING AREA



TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



[MEMO]

[MEMO]

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